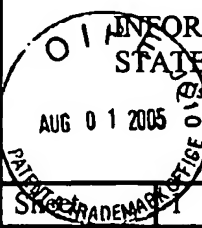


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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	10/824,340	
		Filing Date	April 14, 2004	
		First Named Inventor	Charles W. Extrand	
		Art Unit	1724	
		Examiner Name		
1	of	7	Attorney Docket Number	2267.962US01
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Sheet	2	of	7	Attorney Docket Number	2267.962US01
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NON PATENT LITERATURE DOCUMENTS					
EXAMINER INITIAL¹	Cite No.¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published			T²
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EXAMINER SIGNATURE		DATE CONSIDERED			
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.</p> <p>This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 120 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450.</p> <p>If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.</p>					

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NON PATENT LITERATURE DOCUMENTS					
EXAMINER INITIAL [*]	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published			T ²
KM		R. SHUTTLEWORTH et al., <u>The Spreading of a Liquid Over a Rough Solid</u> , February 23, 1948, pp. 16-22			
		J.F. OLIVER et al., <u>Resistance to Spreading of Liquids by Sharp Edges¹</u> , <i>Journal of Colloid and Interface Science</i> , May 1977, vol. 59, no. 3, pp. 568-579			
		T. ONDA et al., <u>Super-Water-Repellent Fractal Surfaces</u> , <i>The ACS Journal of Surfaces and Colloids</i> , May 1, 1996, vol. 12, no. 9, pp. 2125-2127			
		PHILLIP G. WAPNER et al., <u>Partial Wetting Phenomena on Nonplanar Surfaces and in Shaped Microchannels</u> , <i>Langmuir</i> , 2002, vol. 18, no. 4, pp. 1225-1230			
↓		JOONWON KIM et al., <u>Nanostructured Surfaces for Dramatic Reduction of Flow Resistance in Droplet-Based Microfluidics</u> , 2002, pp. 479-482			
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